

# Kay-Obbe Voss

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/8547655/publications.pdf>

Version: 2024-02-01

9  
papers

93  
citations

1684188  
5  
h-index

1474206  
9  
g-index

9  
all docs

9  
docs citations

9  
times ranked

128  
citing authors

#	ARTICLE	IF	CITATIONS
1	Energy Deposition by Ultrahigh Energy Ions in Large and Small Sensitive Volumes. IEEE Transactions on Nuclear Science, 2022, 69, 241-247.	2.0	1
2	Single Event Effects Characterization of the Programmable Logic of Xilinx Zynq-7000 FPGA Using Very/Ultra High-Energy Heavy Ions. IEEE Transactions on Nuclear Science, 2021, 68, 36-45.	2.0	11
3	A Heavy-Ion Beam Monitor Based on 3-D NAND Flash Memories. IEEE Transactions on Nuclear Science, 2021, 68, 884-889.	2.0	5
4	Heavy-Ion Microbeam Studies of Single-Event Leakage Current Mechanism in SiC VD-MOSFETs. IEEE Transactions on Nuclear Science, 2020, 67, 1381-1389.	2.0	36
5	Optimizing Optical Parameters to Facilitate Correlation of Laser- and Heavy-Ion-Induced Single-Event Transients in SiGe HBTs. IEEE Transactions on Nuclear Science, 2019, 66, 359-367.	2.0	15
6	Experimental Investigation of the Joint Influence of Reduced Supply Voltage and Charge Sharing on Single-Event Transient Waveforms in 65-nm Triple-Well CMOS. IEEE Transactions on Nuclear Science, 2018, 65, 1908-1913.	2.0	4
7	Evidence of Pulse Quenching in AND and OR Gates by Experimental Probing of Full Single-Event Transient Waveforms. IEEE Transactions on Nuclear Science, 2018, 65, 382-390.	2.0	5
8	Microbeam SEE Analysis of MIM Capacitors for GaN Amplifiers. IEEE Transactions on Nuclear Science, 2018, 65, 732-738.	2.0	2
9	Experimental Investigation of Single-Event Transient Waveforms Depending on Transistor Spacing and Charge Sharing in 65-nm CMOS. IEEE Transactions on Nuclear Science, 2017, 64, 2136-2143.	2.0	14